Docket: 71013 Appl. No. 09/640,318

Amendment dated January 26, 2005

PATENT

Amendments to the Specification

Please replace the paragraph beginning at page 21, line 14, with the following paragraph:

The thickness or non-uniformity of thickness measurements can be made off-line after manufacture of the film or preform. For example, they can be used off-line to inspect the film or preform as part of quality control. For example, the measurements can be used to ensure that the film or preform thickness is within the intended range of thickness. Alternatively, the measurements can be made on-line during the manufacture of the film or preform. For example, they can be made on-line as an active system control during the manufacturing process. The thicknesses or non-uniformities of thickness of multiple layers can be simultaneously determined and controlled by monitoring the flourescense fluorescence of the fluorophore compounds (each with a different emission spectra) in each of the multiple layers and using the information to control the molding process.